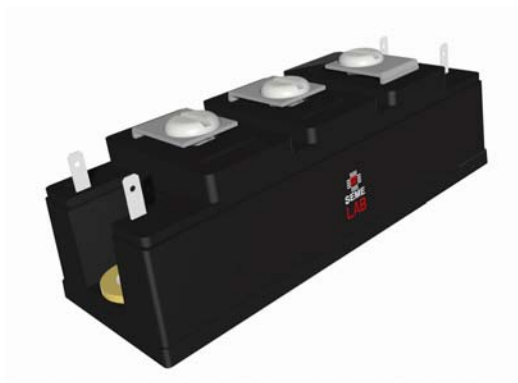


SML100HB06

Attributes:

- aerospace build standard
- high reliability
- lightweight
- metal matrix base plate
- AlN isolation


**Maximum rated values/
Electrical Properties**

Collector-emitter Voltage		V_{ces}	600	V
DC Collector Current	$T_c=75C$	$I_{c, nom}$	100	A
	$T_c=25C$	I_c	130	A
Repetitive peak Collector Current	$tp=1msec, T_c=75C$	I_{crm}	200	A
Total PowerDissipation	$T_c=25C$	P_{tot}	340	W
Gate-emitter peak voltage		V_{ges}	+/-20	V
DC Forward Diode Current		I_f	100	A
Repetitive Peak Forward Current	$tp=1msec$	I_{frm}	200	A
I^2t value per diode	$V_f=0V, tp=10msec, T_vj=125C$	I^2_t	1250	A^2sec
Isolation test voltage	RMS, 50Hz, $t=1min$	V_{isol}	2500	V

Collector-emitter saturation voltage	$I_c=75A, V_{ge}=15V, T_c=25C$	$V_{ce(sat)}$	1.95	2.45	V	
	$I_c=75A, V_{ge}=15V, T_c=125C$		2.2			
Gate Threshold voltage	$V_{ce}=V_{ge}, T_vj=25C$	$V_{ge(th)}$	4.5	5.5	6.5	V
Input capacitance	$f=1MHz, T_vj=25C, V_{ce}=25V, V_{ge}=0V$	C_{ies}	4.3			nF
Reverse transfer Capacitance	$f=1MHz, T_vj=25C, V_{ce}=25V, V_{ge}=0V$	C_{res}	0.4			nF
Collector emitter cut off current	$V_{ce}=600V, V_{ge}=0V, T_vj=25C$	I_{ces}	1	500	μA	
	$V_{ce}=600V, V_{ge}=0V, T_vj=125C$		1			
Gate emitter cut off current	$V_{ce}=0V, V_{ge}=20V, T_vj=25C$	I_{ges}		400	μA	



Turn on delay time	Ic=100A, Vcc=300V Vge=+/15V,Rg=2.2Ω,Tvj=25C Vge=+/-15V,Rg=2.2Ω,Tvj=125C	$t_{d,on}$		25 26		nsec nsec
Rise time	Ic=100A, Vcc=300V Vge=+/-15V,Rg=2.2Ω,Tvj=25C Vge=+/-15V,Rg=2.2Ω,Tvj=125C	t_r		10 11		nsec nsec
Turn off delay time	Ic=100A, Vcc=300V Vge=+/-15V,Rg=2.2Ω,Tvj=25C Vge=+/-15V,Rg=2.2Ω,Tvj=125C	$t_{d,off}$		130 150		nsec nsec
Fall time	Ic=100A, Vcc=300V Vge=+/-15V,Rg=2.2Ω,Tvj=25C Vge=+/-15V,Rg=2.2Ω,Tvj=125C	t_f		20 30		nsec nsec
Turn energy loss per pulse	Ic=75A,Vce=300V,Vge=15V Rge=2.7Ω,Tvj=125C,L=35mH	E_{on}		1.0		mJ
Turn off energy loss per pulse	Ic=75A,Vce=300V,Vge=15V Rge=Ω,Tvj=125C,L=30mH	E_{off}		2.9		mJ
SC Data	$t_p \leq 10\mu\text{sec}$, $V_{ge} \leq 15V$ $T_{vj} \leq 125C$, $V_{ce} = 300V$, $V_{ce(max)} - V_{ces} = 10 di/dt$	I_{sc}		450		A
Stray Module inductance		$L_{\sigma ce}$		40		nH
Terminal-chip resistance		R_c		1.0		mΩ

Diode characteristics

Forward voltage	Ic=75A,Vge=0V, Tc=25C Ic=75A,Vge=0V, Tc=125C	V_f		1.25 1.2	1.6	V
Peak reverse recovery current	If=75A, -di/dt=3000A/μsec Vce=300V,Vge=-10V,Tvj=25C Vce=300V,Vge=-10V,Tvj=125C	I_{rm}		150 180		A
Recovered charge	If=75A, -di/dt=3000A/μsec Vce=600V,Vge=-10V,Tvj=25C Vce=600V,Vge=-10V,Tvj=125C	Q_r		7.7 13		μC
Reverse recovery energy	If=75A, -di/dt=3000A/μsec Vce=600V,Vge=-10V,Tvj=25C Vce=600V,Vge=-10V,Tvj=125C	E_{rec}		3.2		mJ mJ

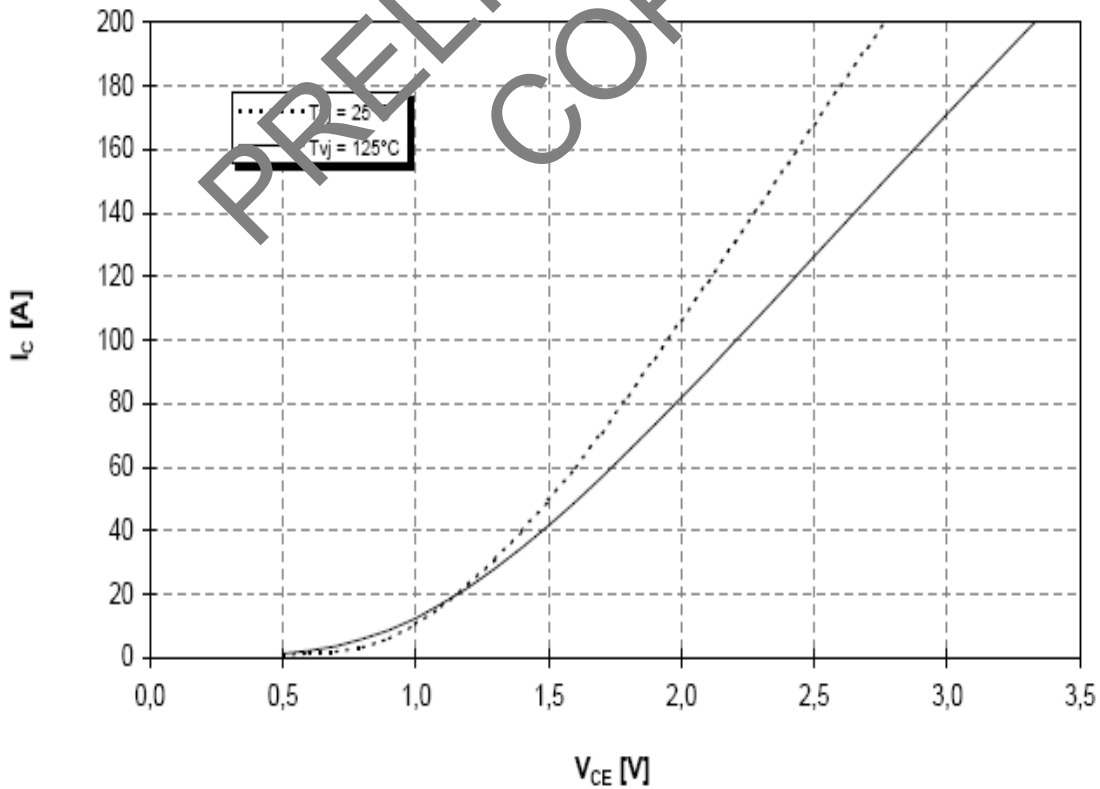


Thermal Properties

Min Typ Max

Thermal resistance junction to case	Igbt Diode	$R_{\theta J-C}$			0.37 0.67	K/W
Thermal resistance case to heatsink		$R_{\theta C-HS}$		0.03		K/W
Maximum junction temperature		T_{vj}			150	C
Maximum operating temperature		T_{op}	-40		125	C
Storage Temperature		T_{stg}	-40		125	C

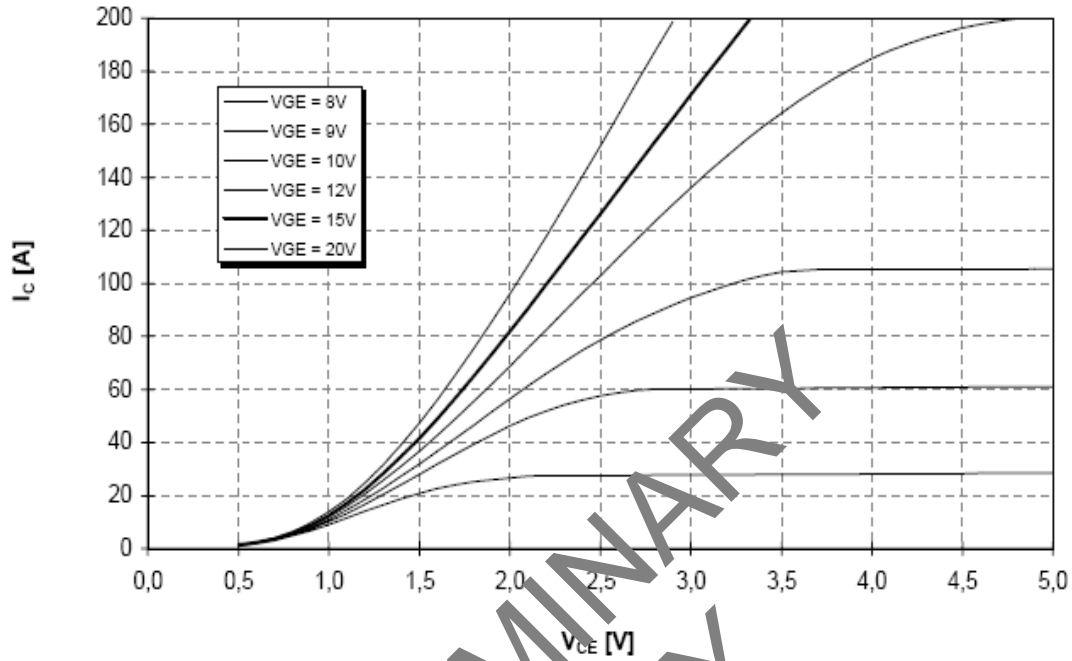
Output characteristic (typical) $V_{GE} = 15V$





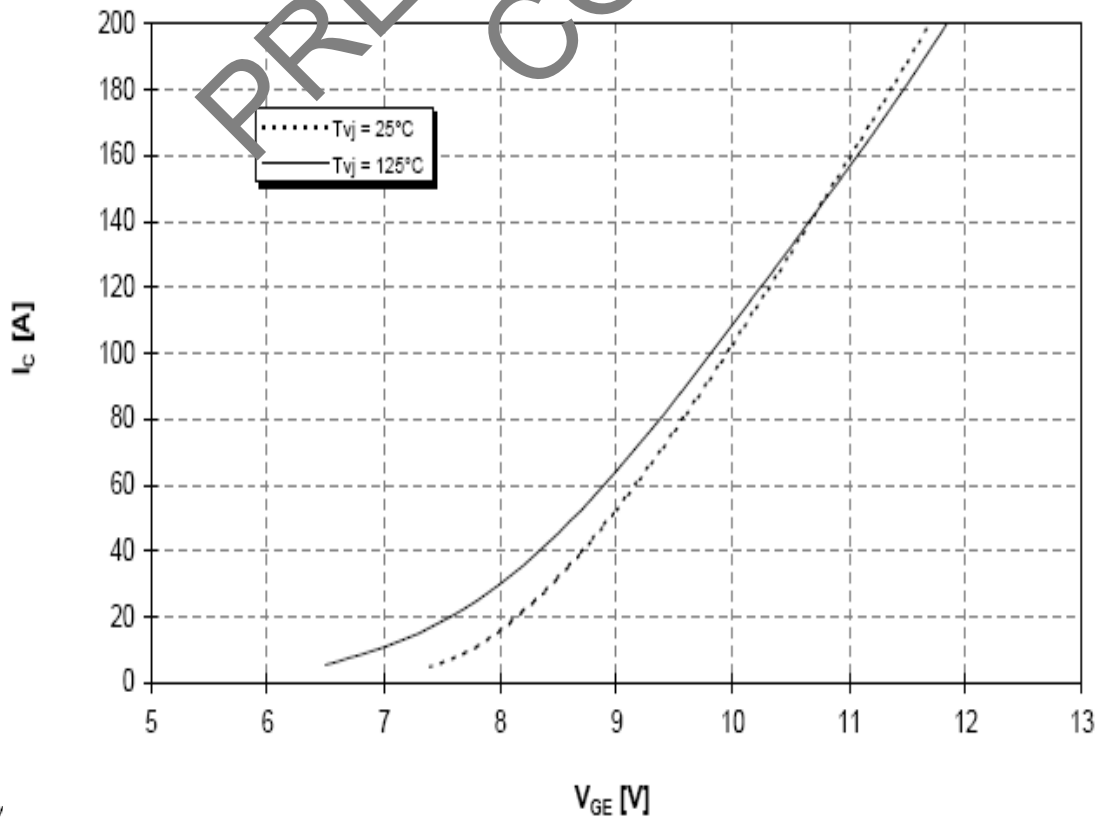
Output characteristic (typical)

$T_{vj} = 125^{\circ}\text{C}$



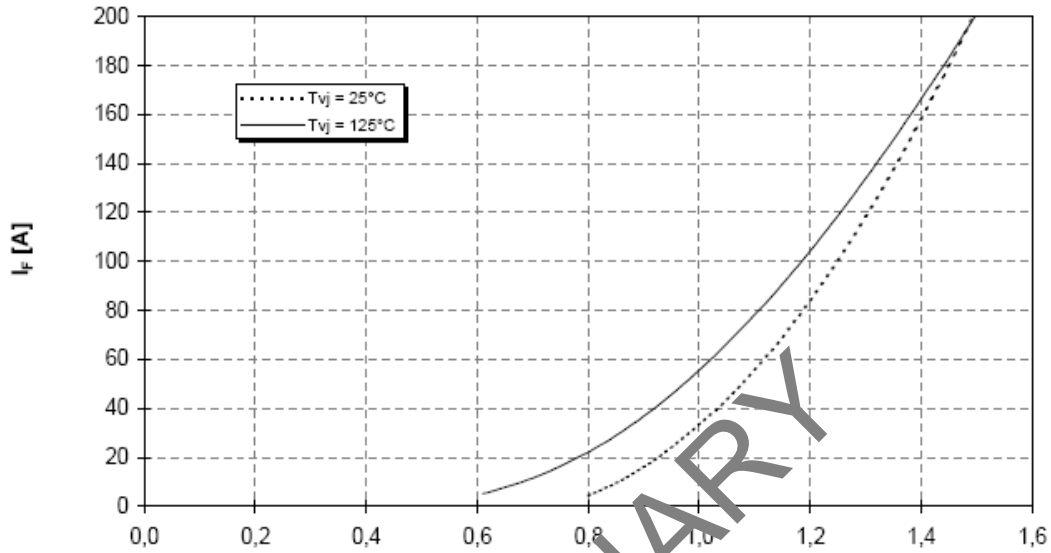
Transfer characteristic (typical)

$V_{ce} = 20V$



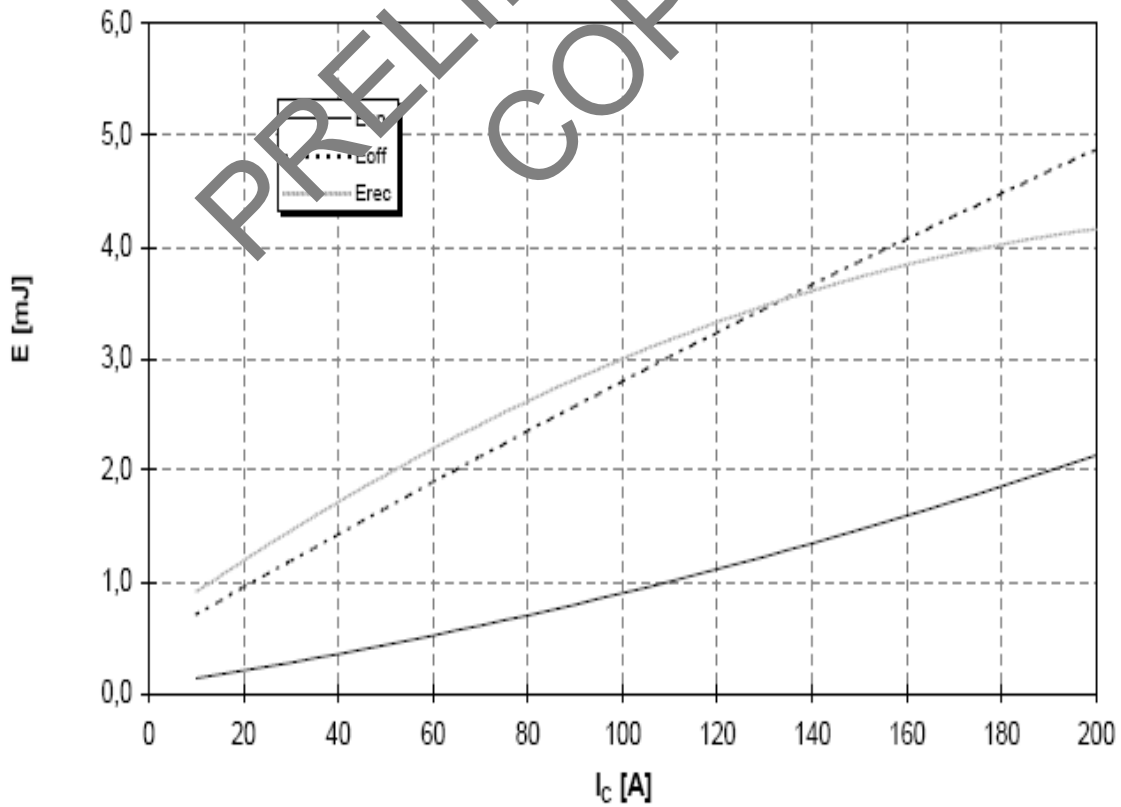


Forward characteristic of inverse diode (typical)



Switching losses (typical)

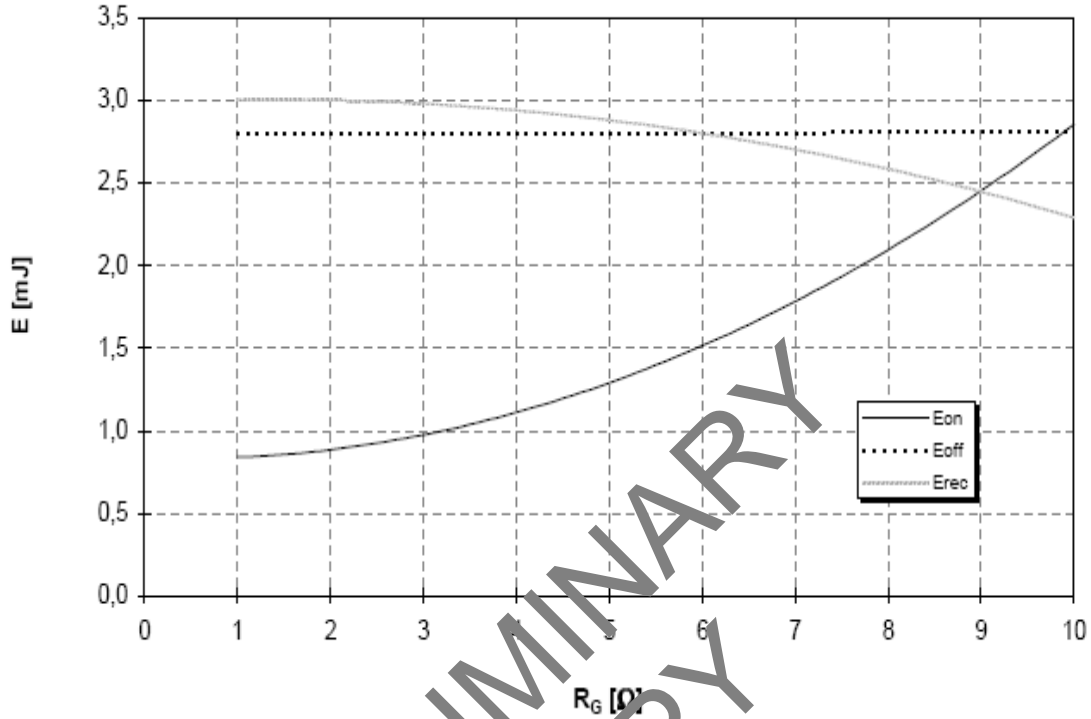
$R_{\theta, on} = 4,0\Omega$, $R_{\theta, off} = 2,2\Omega$, $V_{CC} = 300\text{V}$, $T_{vj} = 125^\circ\text{C}$





Switching losses (typical)

$I_C = 100A$, $V_{CE} = 300V$, $T_V = 125^\circ C$



Reverse bias safe operation area (RBSOA)

$V_{GE} = +15V$, $R_{G,off} = 2,2\Omega$, $T_V = 125^\circ C$

